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ì	Notice of Reference	s Cited	Application/Control No. O9/888,642 Applicant(s)/Patent Under Reexamination HABA ET AL.		on
		s oneu	Examiner CONSIDER	2 Art Unit 1753	Page 1 of 1
			U.S. PATENT DOCUMENTS		
*	Document Number Date Country Code-Number-Kind Code MM-YYYY		Name		Classification
	112 4 444 444				

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,444,110	09-2002	Barstad et al.	205/123
	В	US-6,261,433	07-2001	Landau, Uziel	205/96
	С	US-			/
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	_	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	a					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Gerenrot et al., "Effect of the Structure of Carbocyanine Dyes on the Leveling Power During the Electrodeposition of Copper", Zashchita Metallov (no month, 1972), Vol. 8, No. 3, pp. 338-342.
	٧	
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	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination HABA ET AL. | Examiner | Edna Wong | Art Unit | 1753 | Page 1 of 2

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5,174,886	12-1992	King et al.	205/125
	В	US-4,555,315	11-1985	Barbieri et al.	205/296
*	С	US-6,444,110	09-2002	Barstad et al.	205/123
*	D	US-6,261,433	07-2001	Landau, Uziel	205/96
	E	US-			
	F	US-			
	G.	US-			
	Η	US-			
	_	US-			
	J	US-			
	К	US-			
	L	US-			
	м	US- · /			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	JP 2001003191 A	01-2001	Japan	BARSTAD et al.	C25D 03/38
*	0	JP 2000345392 A	12-2000	Japan	MISHIMA et al.	C25D 07/12
*	Р	JP 2000195822 A	07-2000	Japan .	OKUBO et al.	H01L 21/288
*	Q	JP 2000080494 A	03-2000	Japan	NAGAI et al.	C25D 03/38
*	R	JP 2000064083 A	02-2000	Japan	MUROYAMA, MASAKAZU	C25D 03/02
*	S	JP 2000219994 A	08-2000	Japan	SONE et al.	C25D 03/38
*	Τ	JP 2000248397 A	09-2000	Japan	KURIHARA, MIKA	C25D 03/38

NON-PATENT DOCUMENTS

		NOTE ATENT BOCONLEGES
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	Gerenrot et al., "Effect of the Structure of Carbocyanine Dyes on the Leveling Power During the Electrodeposition of Copper", Zashchita Metallov (no month, 1972), Vol. 8, No. 3, pp. 338-342.
*	٧	References N-T were cited on the Information Under 37 CFR 1.56(a) dated June 26, 2001.
	w	
	х	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates, Classifications may be US or foreign.

Notice of References Cited Application/Control No. Applicant(s)/Patent Under Reexamination HABA ET AL. Examiner Edna Wong Art Unit Page 2 of 2

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-			
	В	US-			
	С	US-			
	D	US-			·
	Ε	US-			
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	G	US-			
	н	US-			
	ı	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-		·	

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	JP 2000034594 A	02-2000	Japan	OKUBO et al.	C25D 03/38
*	. 0	JP 2001102328 A	04-2001	Japan	FUKADA et al.	H01L 21/288
*	Ρ	JP 2001089896 A	04-2001	Japan	KOBAYASHI et al.	C25D 07/00
*	α	JP 11335888 A	12-1999	Japan		- C25D 03/02
	R					
	s					
	T	,				

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	υ	References N-Q were cited on the Information Under 37 CFR 1.56(a) dated June 26, 2001.
	٧	
	w	
	х	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.